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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

IN RE APPLICATION OF: Joseph T. VERDEYEN et al.

SERIAL NO.: NEW U.S. PCT APPLICATION

FILED: HERewith

INTERNATIONAL APPLICATION NO.: PCT/US00/19536

INTERNATIONAL FILING DATE: July 20, 2000

FOR: ELECTRON DENSITY MEASUREMENT AND PLASMA PROCESS CONTROL SYSTEM  
USING CHANGES IN THE RESONANT FREQUENCY OF AN OPEN RESONATOR  
CONTAINING THE PLASMA

**REQUEST FOR PRIORITY UNDER 35 U.S.C. 119(e)  
AND THE INTERNATIONAL CONVENTION**

Assistant Commissioner for Patents  
Washington, D.C. 20231

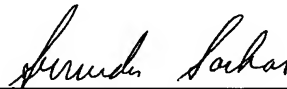
Sir:

In the matter of the above-identified application for patent, notice is hereby given that  
the applicant claims as priority:

<u>COUNTRY</u>	<u>APPLICATION NO</u>	<u>DAY/MONTH/YEAR</u>
USA	60/144,833	21 July 1999

Certified copies of the corresponding Convention application(s) were submitted to the  
International Bureau in PCT Application No. PCT/US00/19536.

Respectfully submitted,  
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